

APPARATUS AND METHOD FOR INSPECTING AND RE-CONDITIONING LEADS
OF IC CHIPS

ABSTRACT

This invention provides an apparatus and system for inspecting and re-conditioning the leads of IC chips. The leads of the chips are scanned to determine their conditions by comparing the images with that of a standard reference; those which do not match the reference image would have the leads re-conditioned and re-scanned, before being sorted for acceptance or rejection.

In concurrent processing, another tray with IC chips having reworkable leads may be input for reworking, just for reconditioning. The chips from the two trays are differentiated and returned to their respective trays, so as to preserve their lot identifications.

Fig. 1